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FQP13N50CF / FQPF13N50CF 500V N-Channel MOSFET

Features

- 13A, 500V, $R_{DS(on)} = 0.54\Omega @V_{GS} = 10 \text{ V}$
- Low gate charge (typical 43 nC)
- Low Crss (typical 20pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- Fast recovery body diode (typical 100ns)

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



Absolute Maximum Ratings

Symbol	1.100 r. COM	Parameter	100 × C.C	FQP13N50CF	FQPF13N50CF	Unit
V _{DSS}	Drain-Source Voltage			500		OVV
I _D	Drain Current	- Continuous (T _C = 25°C)	V 1007.	13	13*	A
	MAN. TOOX.CO	- Continuous (T _C = 100°C	c) 100 X-	8	8*	Α
I _{DM}	Drain Current	- Pulsed	(Note 1)	52	52*	Α
V _{GSS}	Gate-Source voltage			± 30		V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)			530		mJ
I _{AR}	Avalanche Current (Note		(Note 1)	13		AC
E _{AR}	Repetitive Avalanche Energy (Note 1)		(Note 1)	19.5		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns	
P _D	Power Dissipation	(T _C = 25°C)	MM	195	48	W
	MM.I	- Derate above 25°C	WW	1.56	0.39	W/°C
T _{J,} T _{STG}	Operating and Storage Temperature Range			-55 to +150		°C
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			W.100Y.CON	°C	

^{*}Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQP13N50CF	FQPF13N50CF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.64	2.58	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP13N50CF	FQP13N50CF	TO-220	MW.100	M. F.	50
FQPF13N50CF	FQPF13N50CF	TO-220F	1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.	MIL	50

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Off Charac	teristics	CM MMM. COX.CO	TV			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A, T_J = 25^{\circ}C$	500	N		V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	OM_{1}	0.5		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 500V, V _{GS} = 0V)O ₂	TIM	10	μΑ
	WW.100 C	V _{DS} = 400V, T _C = 125°C	$C_{O_{2k}}$	TW.	100	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30V, V_{DS} = 0V$	4 CO)	1 XX	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30V$, $V_{DS} = 0V$		W7	-100	nA
On Charac	teristics	. M.TW W. 10	Di.	OM.T.		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0	C. 1750	4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10V, I _D = 6.5A	100Y.	0.43	0.54	Ω
g _{FS}	Forward Transconductance	$V_{DS} = 40V, I_D = 6.5A$ (Note 4)	$^{1.7}$ 00.2	15	7.7.	S
Dynamic C	Characteristics N	100Y.CO TITW WY	100	V.	MIN	•
C _{iss}	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$		1580	2055	pF
- 11111	Output Capacitance	f = 1.0MHz	Mir	180	235	pF
C _{rss}	Reverse Transfer Capacitance	N.100 T. COM.		20	25	pF
Switching	Characteristics	TATION TO WITH	WIN	100 -	coM	I
t _{d(on)}	Turn-On Delay Time	V _{DD} = 250V, I _D = 13A	1.4	25	60	ns
t _r	Turn-On Rise Time	$R_G = 25\Omega$		100	210	ns
t _{d(off)}	Turn-Off Delay Time			130	270	ns
t _f	Turn-Off Fall Time	(Note 4, 5)	- N	100	210	ns
Qg	Total Gate Charge	V _{DS} = 400V, I _D = 13A	-	43	56	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10V		7.5	100.	nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)	1	18.5	700x	nC
Drain-Sour	ce Diode Characteristics and Maximur	n Ratings		MM	1100	
I _S	Maximum Continuous Drain-Source Dio	de Forward Current		V-W	13	A
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current	1	- N	52	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0V, I _S = 13A	<u></u>	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _S = 13A		100	160	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$ (Note 4)		0.35	17.7	μС

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 5.6mH, I_{AS} = 13A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
- 3. $I_{SD} \le 13A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 4. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2%
- 5. Essentially Independent of Operating Temperature Typical Characteristics

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Typical Performance Characteristics

Figure 1. On-Region Characteristics

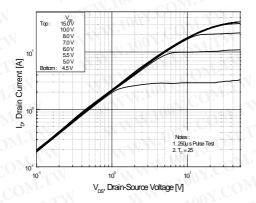


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

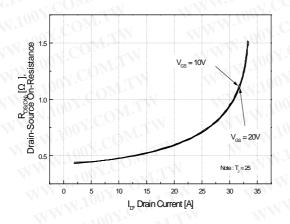


Figure 5. Capacitance Characteristics

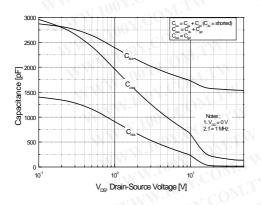


Figure 2. Transfer Characteristics

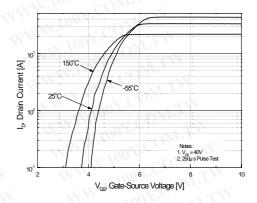


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

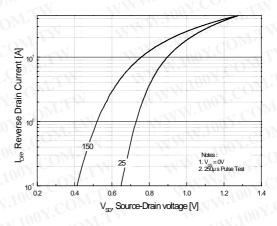
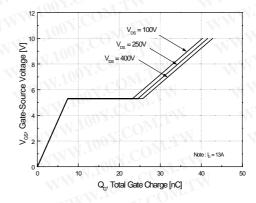


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

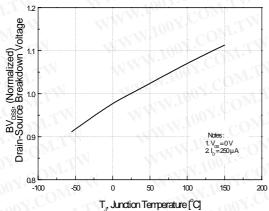
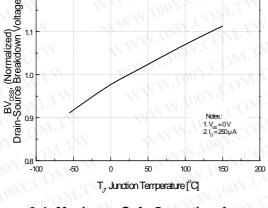


Figure 9-1. Maximum Safe Operating Area for FQP13N50CF



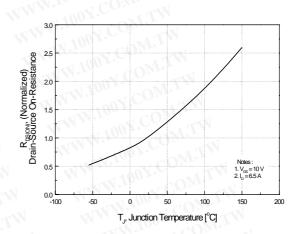


Figure 8. On-Resistance Variation

vs. Temperature

In, Drain Current [A] 10¹ 10° 10 V_{DS}, Drain-SourceVoltage[V]

Figure 10. Maximum Drain Current vs. Case Temperature

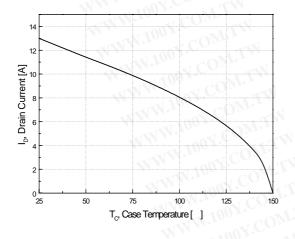
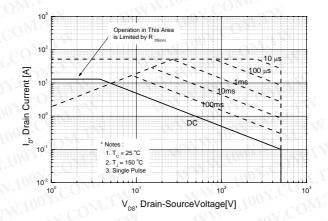
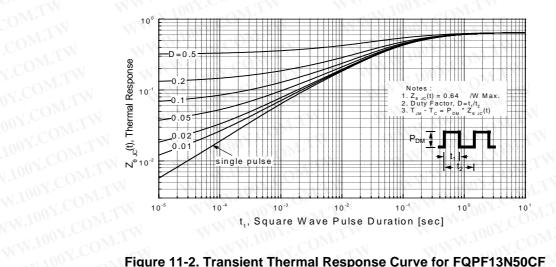


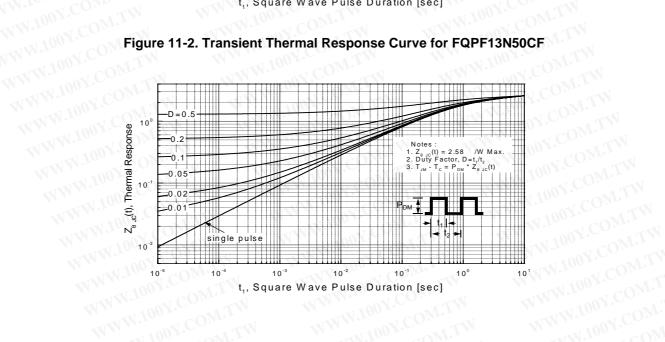
Figure 9-2. Maximum Safe Operating Area for FQPF13N50CF



Typical Performance Characteristics (Continued)

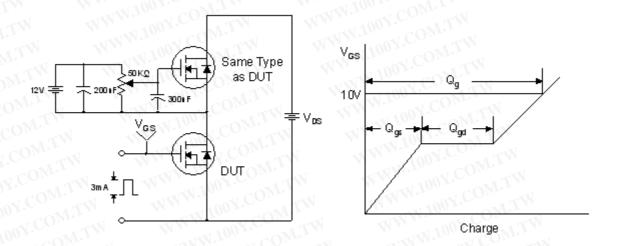
Figure 11-1. Transient Thermal Response Curve for FQP13N50CF



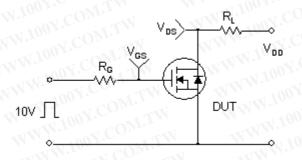


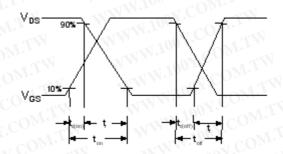
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Gate Charge Test Circuit & Waveform

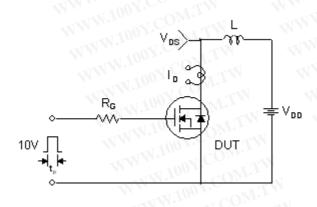


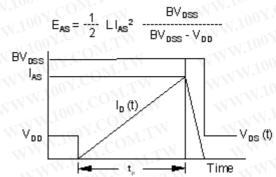
Resistive Switching Test Circuit & Waveforms



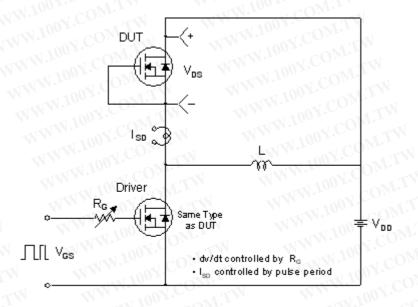


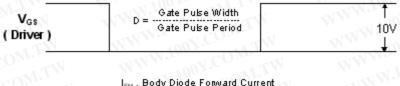
Unclamped Inductive Switching Test Circuit & Waveforms

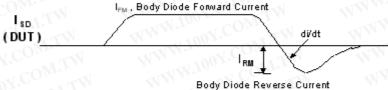


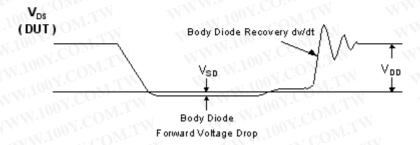


Peak Diode Recovery dv/dt Test Circuit & Waveforms

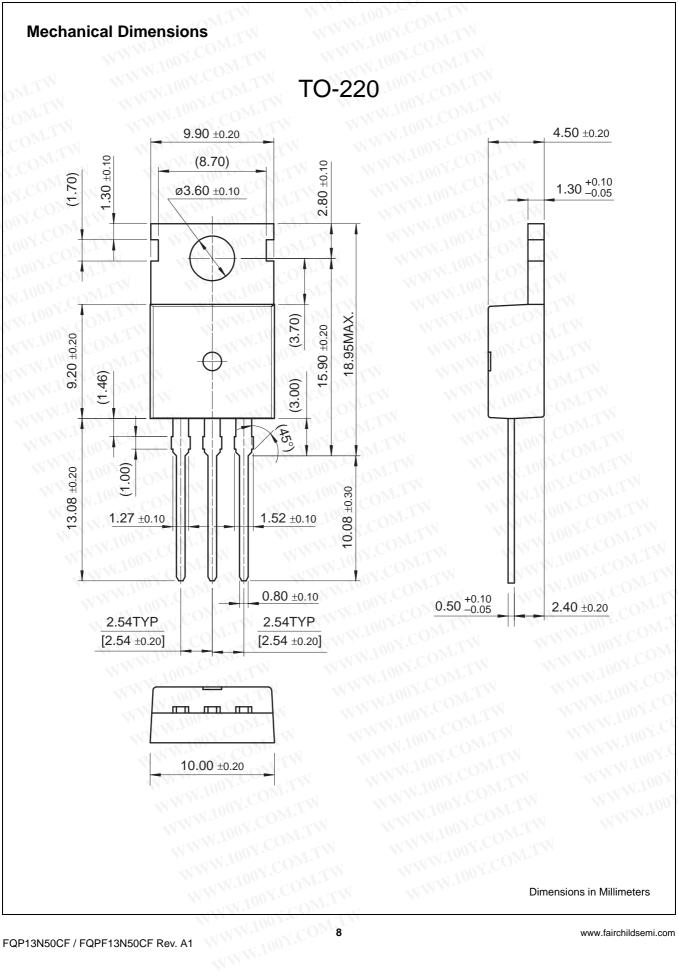








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Mechanical Dimensions (Continued) 3.30 ±0.10 10.16 ±0.20 Ø3.18 ±0.10 2.54 ± 0.20 (7.00)(0.70)6.68 ±0.20 Φ ±0.20 15.87 (1.00x45°) MAX1.47 9.75 ±0.30 0.35 ± 0.10 $0.50^{\,+0.10}_{\,-0.05}$ 2.54TYP 2.54TYP [2.54 ±0.20] [2.54 ±0.20] ±0.20 9.40 ±0.20

Dimensions in Millimeters

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F	ACT Quiet Series	-м	OPTOPLANAR™	SILENT SWITCHER®	UltraFET [®]
Α	cross the board. A	round the world.™	PACMAN™	SMART START™	VCX™
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